



STW34NB20

N-CHANNEL 200V - 0.062 Ω - 34A TO-247

PowerMESH™ MOSFET

Table 1. General Features

| Type | V _{DSS} | R _{DS(on)} | I _D |
|-----------|------------------|---------------------|----------------|
| STW34NB20 | 200 V | < 0.075 Ω | 34 A |

FEATURES SUMMARY

- TYPICAL R_{DS(on)} = 0.062 Ω
- EXTREMELY HIGH dv/dt CAPABILITY
- 100% AVALANCHE TESTED
- VERY LOW INTRINSIC CAPACITANCES
- GATE CHARGE MINIMIZED

DESCRIPTION

Using the latest high voltage MESH OVERLAY™ process, STMicroelectronics has designed an advanced family of power MOSFETs with outstanding performances. The new patent pending strip layout coupled with the Company's proprietary edge termination structure, gives the lowest R_{DS(on)} per area, exceptional avalanche and dv/dt capabilities and unrivalled gate charge and switching characteristics.

APPLICATIONS

- SWITCH MODE POWER SUPPLIES (SMPS)
- DC-AC CONVERTERS FOR WELDING EQUIPMENT AND UNINTERRUPTIBLE POWER SUPPLIES AND MOTOR DRIVE
- HIGH CURRENT, HIGH SPEED SWITCHING

Figure 1. Package

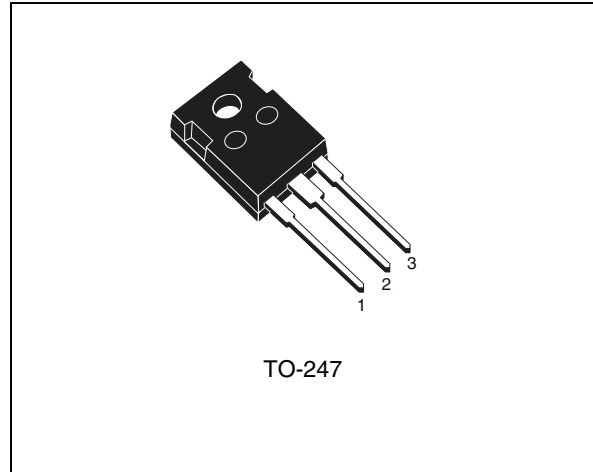


Figure 2. Internal Schematic Diagram

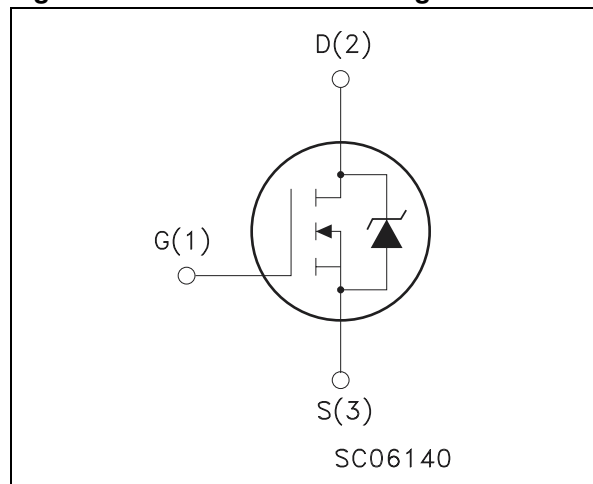


Table 2. Order Codes

| Part Number | Marking | Package | Packaging |
|-------------|---------|---------|-----------|
| STW34NB20 | W34NB20 | TO-247 | TUBE |

Table 3. Absolute Maximum Ratings

| Symbol | Parameter | Value | Unit |
|----------------|--|------------|---------------------|
| V_{DS} | Drain-source Voltage ($V_{GS} = 0$) | 200 | V |
| V_{DGR} | Drain- gate Voltage ($R_{GS} = 20\text{ k}\Omega$) | 200 | V |
| V_{GS} | Gate-source Voltage | ± 30 | V |
| I_D | Drain Current (cont.) at $T_C = 25\text{ }^\circ\text{C}$ | 34 | A |
| I_D | Drain Current (cont.) at $T_C = 100\text{ }^\circ\text{C}$ | 21 | A |
| $I_{DM}^{(1)}$ | Drain Current (pulsed) | 136 | A |
| P_{tot} | Total Dissipation at $T_C = 25\text{ }^\circ\text{C}$ | 180 | W |
| | Derating Factor | 1.44 | W/ $^\circ\text{C}$ |
| T_{stg} | Storage Temperature | -65 to 150 | $^\circ\text{C}$ |
| T_j | Max. Operating Junction Temperature | 150 | $^\circ\text{C}$ |

Note: 1. Pulse width limited by safe operating area

Table 4. Thermal Data

| Symbol | Parameter | Value | Unit |
|----------------|--|-------|---------------------------|
| $R_{thj-case}$ | Thermal Resistance Junction-case Max | 0.69 | $^\circ\text{C}/\text{W}$ |
| $R_{thj-amb}$ | Thermal Resistance Junction-ambient Max | 30 | $^\circ\text{C}/\text{W}$ |
| T_l | Maximum Lead Temperature For Soldering Purpose | 300 | $^\circ\text{C}$ |

Table 5. Avalanche Characteristics

| Symbol | Parameter | Max Value | Unit |
|----------|--|-----------|------|
| I_{AR} | Avalanche Current, Repetitive or Not-Repetitive (pulse width limited by T_j max, $\delta < 1\%$) | 34 | A |
| E_{AS} | Single Pulse Avalanche Energy (starting $T_j = 25\text{ }^\circ\text{C}$; $I_D = I_{AR}$; $V_{DD} = 50\text{ V}$) | 650 | mJ |

ELECTRICAL CHARACTERISTICS ($T_{\text{case}} = 25^{\circ}\text{C}$ unless otherwise specified)**Table 6. Off**

| Symbol | Parameter | Test Conditions | Min. | Typ. | Max. | Unit |
|-----------------------------|---|--|------|------|-----------|---------------|
| $V_{(\text{BR})\text{DSS}}$ | Drain-source Breakdown Voltage | $I_{\text{D}} = 250 \mu\text{A}$ $V_{\text{GS}} = 0$ | 200 | | | V |
| I_{DSS} | Zero Gate Voltage | $V_{\text{DS}} = \text{Max Rating}$ | | | 1 | μA |
| | Drain Current ($V_{\text{GS}} = 0$) | $V_{\text{DS}} = \text{Max Rating}$ $T_{\text{c}} = 125^{\circ}\text{C}$ | | | 10 | μA |
| I_{GSS} | Gate-body Leakage Current ($V_{\text{DS}} = 0$) | $V_{\text{GS}} = \pm 30 \text{ V}$ | | | ± 100 | nA |

Table 7. On ⁽¹⁾

| Symbol | Parameter | Test Conditions | Min. | Typ. | Max. | Unit |
|---------------------|-----------------------------------|--|------|-------|-------|----------|
| $V_{\text{GS(th)}}$ | Gate Threshold Voltage | $V_{\text{DS}} = V_{\text{GS}}$; $I_{\text{D}} = 250 \mu\text{A}$ | 3 | 4 | 5 | V |
| $R_{\text{DS(on)}}$ | Static Drain-source On Resistance | $V_{\text{GS}} = 10\text{V}$; $I_{\text{D}} = 17 \text{ A}$ | | 0.062 | 0.075 | Ω |

Note: 1. Pulsed: Pulse duration = 300 μs , duty cycle 1.5 %**Table 8. Dynamic**

| Symbol | Parameter | Test Conditions | Min. | Typ. | Max. | Unit |
|--------------------------------|------------------------------|--|------|------|------|------|
| g_{fs} ⁽¹⁾ | Forward Transconductance | $V_{\text{DS}} > I_{\text{D(on)}} \times R_{\text{DS(on)max}}$; $I_{\text{D}} = 17 \text{ A}$ | 8 | 17 | | S |
| C_{iss} | Input Capacitance | $V_{\text{DS}} = 25 \text{ V}$; $f = 1 \text{ MHz}$; $V_{\text{GS}} = 0$ | | 2400 | 3300 | pF |
| C_{oss} | Output Capacitance | | | 650 | 900 | pF |
| C_{rss} | Reverse Transfer Capacitance | | | 90 | 130 | pF |

Note: 1. Pulsed: Pulse duration = 300 μs , duty cycle 1.5 %**Table 9. Switching On**

| Symbol | Parameter | Test Conditions | Min. | Typ. | Max. | Unit |
|--------------------|--------------------|--|------|------|------|------|
| $t_{\text{d(on)}}$ | Turn-on Time | $V_{\text{DD}} = 100 \text{ V}$; $I_{\text{D}} = 17 \text{ A}$; $R_{\text{G}} = 4.7 \Omega$ | | 30 | 40 | ns |
| t_{r} | Rise Time | $V_{\text{GS}} = 10 \text{ V}$ (see test circuit, Figure 16) | | 40 | 55 | ns |
| Q_{g} | Total Gate Charge | $V_{\text{DD}} = 160 \text{ V}$; $I_{\text{D}} = 34 \text{ A}$; $V_{\text{GS}} = 10 \text{ V}$ | | 60 | 80 | nC |
| Q_{gs} | Gate-Source Charge | | | 19 | | nC |
| Q_{gd} | Gate-Drain Charge | | | 29 | | nC |

Table 10. Switching Off

| Symbol | Parameter | Test Conditions | Min. | Typ. | Max. | Unit |
|----------------------|-----------------------|---|------|------|------|------|
| $t_{\text{r(Voff)}}$ | Off-voltage Rise Time | $V_{\text{DD}} = 160 \text{ V}$; $I_{\text{D}} = 34 \text{ A}$; $R_{\text{G}} = 4.7 \Omega$ $V_{\text{GS}} = 10 \text{ V}$ (see test circuit, Figure 18) | | 17 | 23 | ns |
| t_{f} | Fall Time | | | 18 | 24 | ns |
| t_{c} | Cross-over Time | | | 35 | 47 | ns |

Table 11. Source Drain Diode

| Symbol | Parameter | Test Conditions | Min. | Typ. | Max. | Unit |
|-----------------|-------------------------------|--|------|------|------|---------------|
| I_{SD} | Source-drain Current | | | | 34 | A |
| $I_{SDM}^{(1)}$ | Source-drain Current (pulsed) | | | | 136 | A |
| $V_{SD}^{(2)}$ | Forward On Voltage | $I_{SD} = 34\text{ A}; V_{GS} = 0$ | | | 1.5 | V |
| t_{rr} | Reverse Recovery Time | $I_{SD} = 34\text{ A}; di/dt = 100\text{ A}/\mu\text{s}$ | | | 290 | ns |
| Q_{rr} | Reverse RecoveryCharge | $V_{DD} = 50\text{ V}; T_j = 150\text{ }^\circ\text{C}$ (see test circuit, Figure 18) | | | 2.7 | μC |
| I_{RRAM} | Reverse RecoveryCharge | | | | 18.5 | A |

Note: 1. Pulse width limited by safe operating area
 2. Pulsed: Pulse duration = 300 μs , duty cycle 1.5 %

Figure 3. Safe Operating Area

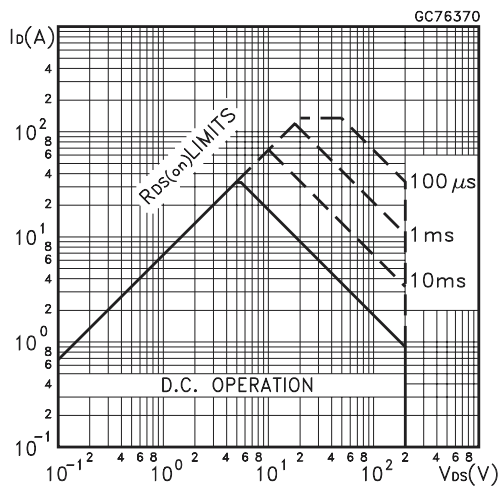


Figure 4. Thermal Impedance

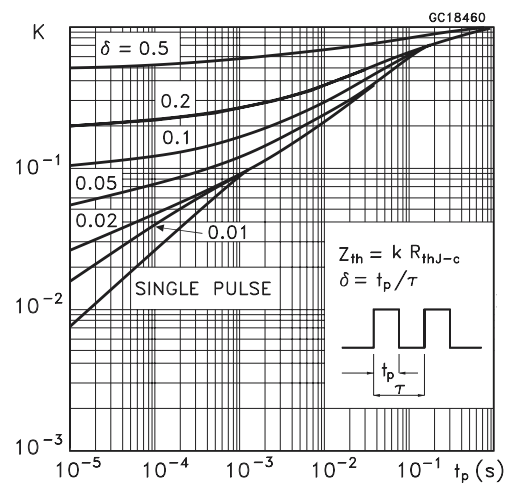


Figure 5. Output Characteristics

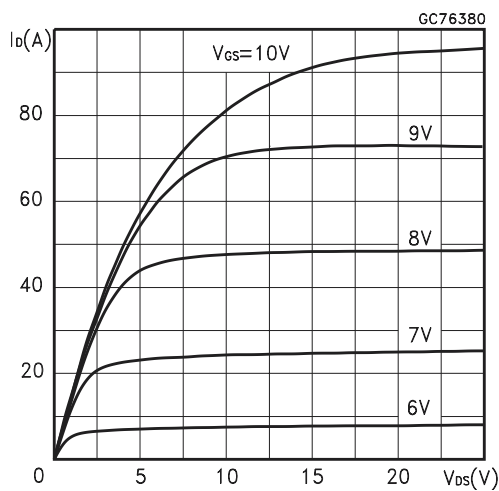


Figure 6. Transfer Characteristics

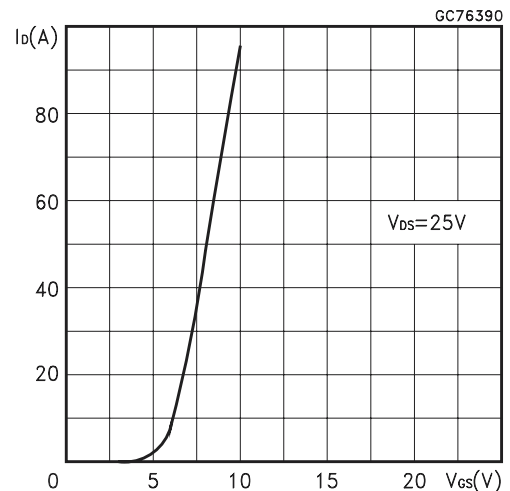


Figure 7. Transconductance

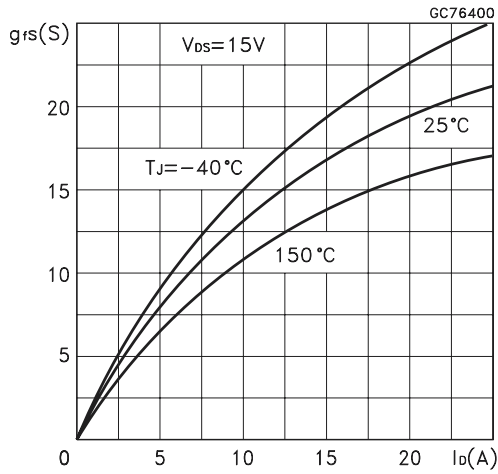


Figure 8. Static Drain-source On Resistance

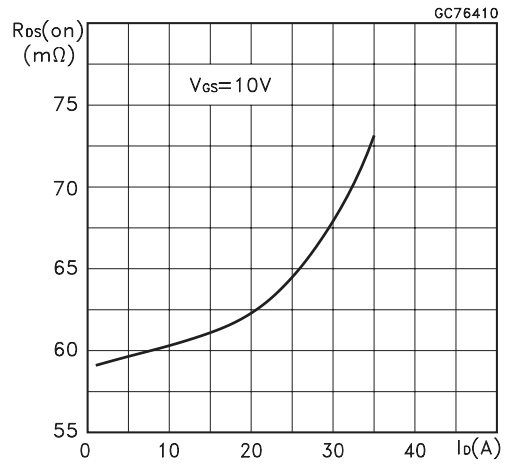


Figure 9. Gate Charge vs Gate-source Voltage

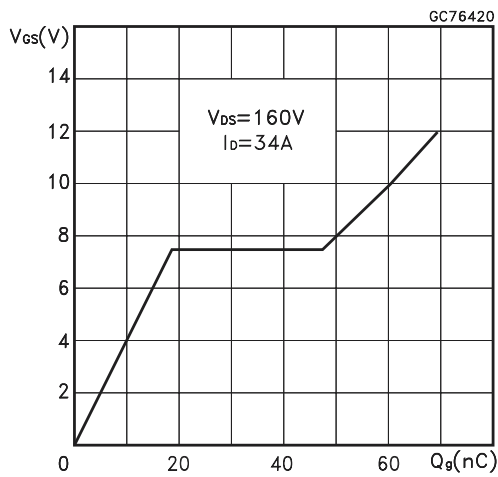


Figure 10. Capacitance Variations

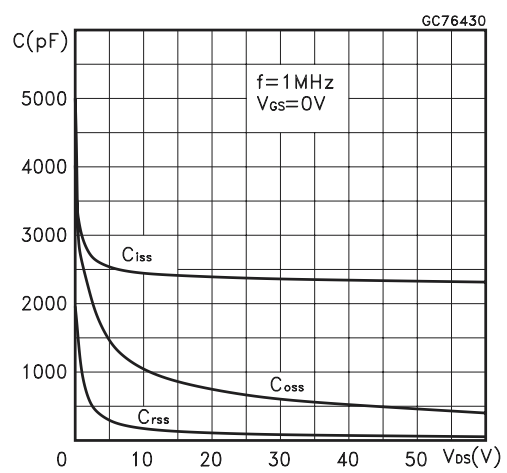


Figure 11. Normalized Gate Threshold Voltage vs Temperature

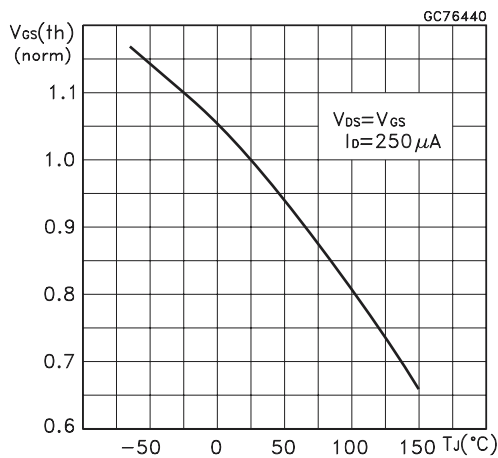


Figure 12. Normalized On Resistance vs Temperature

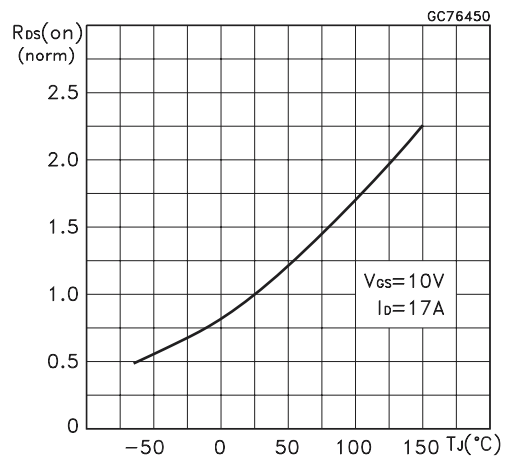


Figure 13. Source-drain Diode Forward Characteristics

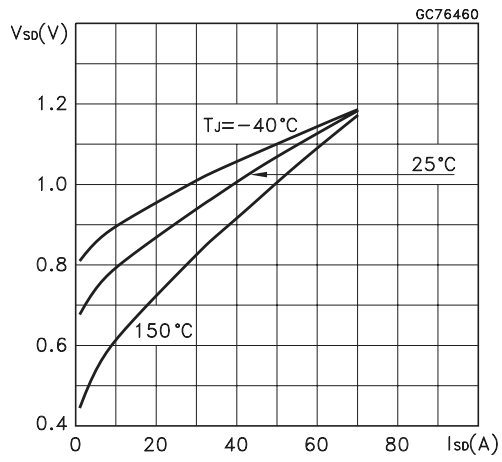


Figure 14. Unclamped Inductive Load Test Circuit

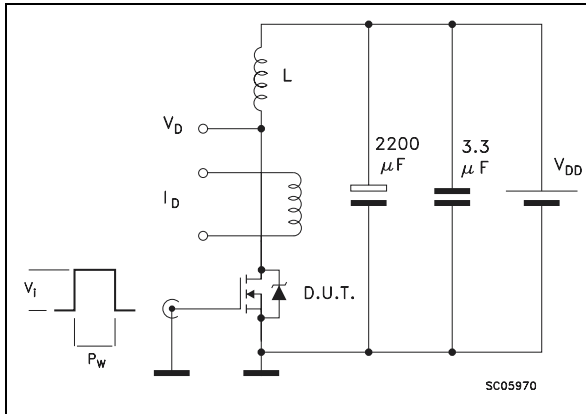


Figure 15. Unclamped Inductive Waveforms

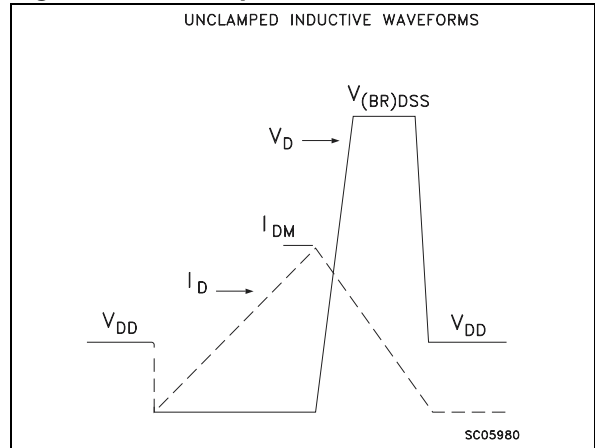


Figure 16. Switching Times Test Circuits For Resistive Load

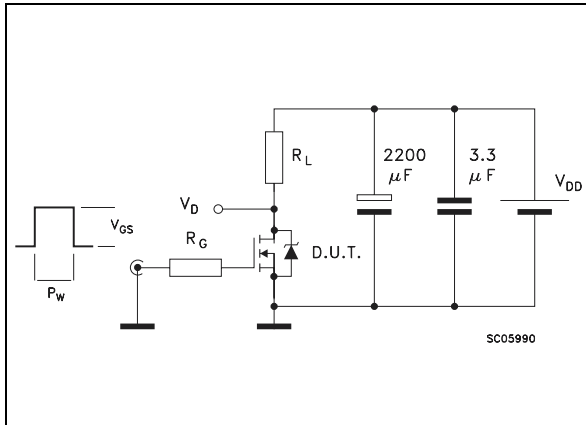


Figure 17. Gate Charge Test Circuit

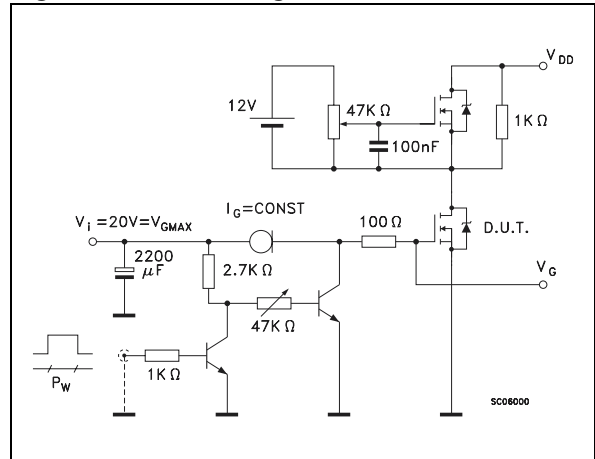
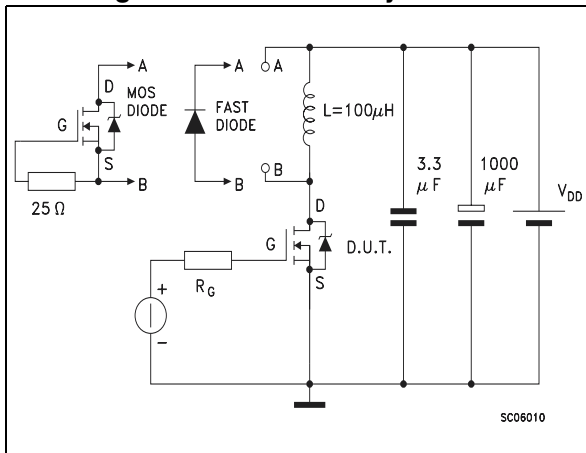


Figure 18. Test Circuit For Inductive Load Switching And Diode Recovery Times

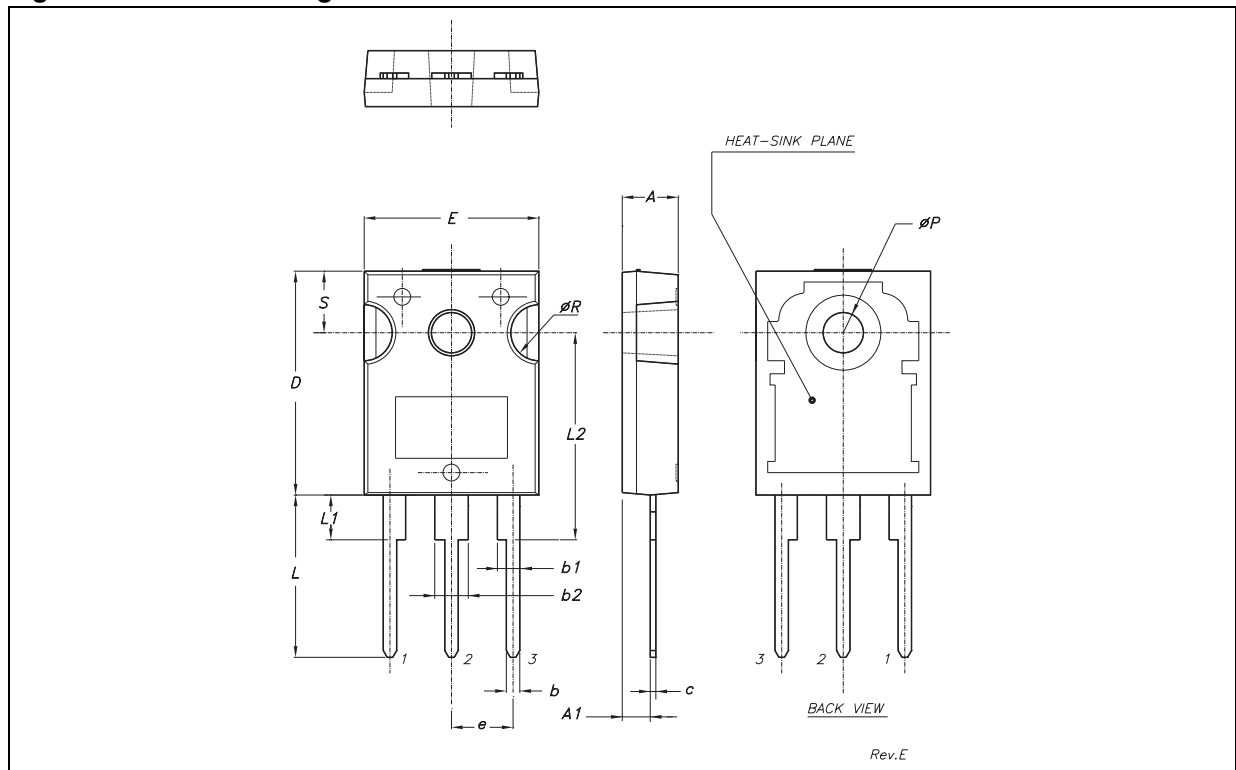


PACKAGE MECHANICAL

Table 12. TO-247 Mechanical Data

| Symbol | millimeters | | | inches | | |
|--------|-------------|-------|-------|--------|-------|-------|
| | Min | Typ | Max | Min | Typ | Max |
| A | 4.85 | | 5.15 | 0.19 | | 0.20 |
| A1 | 2.20 | | 2.60 | 0.086 | | 0.102 |
| b | 1.0 | | 1.40 | 0.039 | | 0.055 |
| b1 | 2.0 | | 2.40 | 0.079 | | 0.094 |
| b2 | 3.0 | | 3.40 | 0.118 | | 0.134 |
| c | 0.40 | | 0.80 | 0.015 | | 0.03 |
| D | 19.85 | | 20.15 | 0.781 | | 0.793 |
| E | 15.45 | | 15.75 | 0.608 | | 0.620 |
| e | | 5.45 | | | 0.214 | |
| L | 14.20 | | 14.80 | 0.560 | | 0.582 |
| L1 | 3.70 | | 4.30 | 0.14 | | 0.17 |
| L2 | | 18.50 | | | 0.728 | |
| ØP | 3.55 | | 3.65 | 0.140 | | 0.143 |
| ØR | 4.50 | | 5.50 | 0.177 | | 0.216 |
| S | | 5.50 | | | 0.216 | |

Figure 19. TO-247 Package Dimensions



Note: Drawing is not to scale.

REVISION HISTORY**Table 13. Revision History**

| Date | Revision | Description of Changes |
|--------------|-----------------|---------------------------------------|
| January-1998 | 1 | First Issue |
| 14-Apr-2004 | 2 | Stylesheet update. No content change. |

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